From the Editor

Microscopy Today Innovation Awards

The *Microscopy Today* Innovation Awards were established to honor innovative microscopy-related products and methods that appeared in the previous year. Winning products and methods are selected on the basis of their importance and usefulness to the microscopy community. The innovations most likely to win are those that provide better, faster, or entirely new methods of analysis by some type of microscope or microanalytical instrument.

The Evaluation Committee, under the leadership of Tom Kelly, looked for innovations that will allow new and impactful experimental investigations. There were many innovative products and methods nominated, making selection of the awardees difficult. The following ten innovations received the 2010 awards:

Adaptive Band Excitation in scanning probe microscopy
JEOL Clairscope™ integrated light microscope/SEM
Direct Electron DDD sensor that detects individual electrons
Dynamic Transmission Electron Microscope (DTEM)
Nanonics Hydra™ MultiProbe BioScanned Probe Microscope
Luminace Contrast illumination for light microscopy
Agilent/Novelx "mySEM" with electrostatic electron optics
Fischione Model 1040 NanoMill TEM specimen preparation system
FEI Tecnai Osiris™ Scanning/Transmission Electron Microscope
Ultra-high-resolution atomic imaging of surfaces and bulk materials

Descriptions of these innovations are given in an article within this issue. Congratulations to the developers of these instruments and methods.

Details of the nomination process for the 2011 *Microscopy Today* Innovation Awards will be posted on the *Microscopy Today* website (www.microscopy-today.com) on November 1, 2010. Nomination applications for the 2011 awards will be accepted through March 1, 2011.

Charles Lyman
Editor-in-Chief

Publication Objective: to provide information of interest to microscopists.

Microscopy Today is a controlled-circulation trade magazine owned by the Microscopy Society of America that is published six times a year in the odd months. Editorial coverage spans all microscopy techniques including light microscopy, scanning probe microscopy, electron microscopy, ion-beam techniques, and the wide range of microanalytical methods. Readers and authors come from both the life sciences and the physical sciences. The typical length of an article is about 2,000 words plus figures and tables; feature articles are longer. Interested authors should consult "Instructions for Contributors" on the *Microscopy Today* website: www.microscopy-today.com.

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